

*Indian Standard*

**GUIDE ON METHODS OF MEASUREMENT OF SHORT  
DURATION TRANSIENTS ON LOW VOLTAGE POWER  
AND SIGNAL LINES**

NATIONAL FOREWORD

This Indian Standard which is identical with IEC Pub 816 (1984) 'Guide on methods of measurement of short duration transients on low voltage power and signal lines', issued by International Electrotechnical Commission (IEC), was adopted by the Bureau of Indian Standards on 21 March 1989, on the recommendation of the Electromagnetic Compatibility Sectional Committee (LTDC 22) and approval of the Electronics and Telecommunication Division Council.

In the adopted standard certain terminology and conventions are not identical with those used in Indian Standards, attention is particularly drawn to the following:

- a) Wherever the words 'International Standard' appear referring to this standard. they should be read as 'Indian Standard'.
- b) Comma (,) has been used as a decimal marker while in Indian Standards the current practice is to use a point (.) as the decimal marker.

CROSS REFERENCES

The Electromagnetic Compatibility Sectional Committee has reviewed the provisions of the following IEC Publications and has decided that they are acceptable for use in conjunction with this Indian Standard:

IEC Pub 27: Letter symbols to be used in electrical technology

IEC Pub 50: International electrotechnical vocabulary (IEV)

IEC Pub 617: Graphical symbols for diagrams

Only the English language text in the International Standard has been retained while adopting it in this Indian Standard. As a result of dropping the French text, the consequential changes in page numbers have been effected

**1. Scope**

This report is intended to give guidance on methods of measurement of short duration transients on low voltage power and signal lines.